



Fraunhofer
ENAS

European Test and Reliability Center

Innovation needs Trust

Opening
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www.enas.fraunhofer.de/etrc



Precise testing.
Valid reliability
assessments.
Future-proof
technologies.

The European Test and Reliability Center (ETRC) at Fraunhofer ENAS is a unique center of excellence in Europe for testing and reliability assessments of future semiconductor innovations.

Combining cutting-edge infrastructure, in-depth expertise and a strong network of academia and industry, the ETRC provides reliable solutions ensuring the quality, performance and durability of pioneering microtechnologies.

The ETRC covers both research and development of new testing and evaluation methods as well as their optimization for specific applications. In addition, the ETRC offers a broad range of services for the verification of small series and practical consulting for companies. A specialized training and education program enables the targeted qualification of professionals in the field of testing methods and reliability assessments.

Industrialization of cutting-edge testing methods in the following areas

- High-power technologies
- Heterointegration/chiplets
- Optical metrology and photonics
- MEMS sensors
- Inline metrology
- AI-based data models and digital twins
- Design for test and reliability
- Micro- and nanosystem technology/ electronics

Our services for the industry

- Development of testing methods for the validation of semiconductor systems in safety-critical applications
- Implementation of method-driven testing from design to industrial deployment
- Tailored solutions for applications in power electronics, sensors, digital components (CMOS) and optical systems



- Optimization of testing procedures and methods
- Access to state-of-the-art testing methods, including silicon carbide (SiC) and gallium nitride (GaN)
- Development of fast and precise reliability models and lifetime predictions
- Consulting for the development of customer-specific service offerings

Your benefits

- Leading testing and reliability methods from a single source
- Increased product quality
- Reduction of development costs
- Assurance of maximum reliability throughout the entire product life cycle
- Optimized time-to-market strategies
- Fast and successful scaling of robust semiconductor innovations

Contact

European Test
and Reliability Center (ETRC)

Fraunhofer Institute for
Electronic Nano Systems ENAS
Technologie-Campus 3
09126 Chemnitz
Germany

Phone +49 371 45001-0
info@enas.fraunhofer.de

www.enas.fraunhofer.de

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